12 Microscopy

Microscope is an optical system designed for the seen by the unaidad study of objects not to be seen by the unaided eye. makes us see things which are very small and which are skonein - to sk otherwise invisible (Mikros = small; skopein = to see, to look). It is an inevitable instrument for clinical and laboratory studies. The first microscope was designed by



Fig.12.1: Jenssen's compound microscope.

Jenssen's microscope is a compound microscope. It is the first microscope. It contains two tubes fitted one inside the other. Its magnification is

Magnification The optical system of the microscope magnifies the objects to several folds of their original size. The ratio of this magnified image to that formed on retina of an unaided normal eye is termed the magnification.

Size of retinal image seen with microscope Chap. 12: Microscopy ion size of retinal image seen with unaided eye The resolving power is the capacity of an optical The resolving Power of unaided by The re System to show assume the second of unaided human eye is

logether. Thus the human eye can distinguish alice. Ogether. Thus the human eye can distinguish objects upto The resolving power depends on the wave length (1) of light and the numerical aperture (NA) of the The limit of resolution is the minimum distance between two points resolvable as separate points, when objective lens. viewed through lenses.

0.161 Limit of resolution d = ____

NA = Numerical aperture 1 = Wave length of light used. where,

The limit of resolution is inversely proportional to the resolving power. Numerical aperture is limited due to the stability of refractive index of the optical materials, which does not exceed 1.6. Thus it is evident that the resolving power can be increased by reducing the limit of resolution, i.e., by using smaller wave length.

Types of Microscopes

The microscopes are classified into three types based on the source of illumination. They are the following:

தலைக்கழக கள்

- 1. Light microscopes
- 2. Electron microscopes 3. X-ray microscopes.

SaraS Publication

1. Light Microscopes In light microscopes, light is the source of In light interescopes, tight is the source of illumination. They are sub-divided into the following types.

Polarizing microscope

- Simple microscope

 Polarizing microscope

 Dark fiold microscope
- Compound microscope Dark field microscope

 Illtraviolot
- Phase contrast microscope
- Interference microscope

- microscope
- Fluorescence microscope
- Cinematography

Compound Microscope

The compound microscope is an optical instrument to magnify objects.

It is formed by the combination of two simple microscopes (a simple microscope is formed of only one

It is a light microscope because light is the illuminating source. Principle

The compound microscope works on the principle of optics. The lenses magnify objects. By stacking lenses the magnification is increased.

The compound microscope has a light source, a diaphragm, an object an objective lens and an eye piece

The light passes through the diaphragm. The The limage of the object. The light on the object. Enified image of mage acts as an object for the eye
This magnified image acts as an object for the eye agnified image of the object. The eye piece produces a virtual inverted and agnified image of the object. The magnifying power of a compound microscope The magnify ... SP of the final image to the size of Wagnifying Power Size of the final image the object. The magnification of the compound microscope can Size of the object be obtained by multiplying the power of the objective lens and eyepiece. Image of objective Object Light lens Objective lens Eye lens Final image Fig 12.2. Principle of compound microscope.

If the power of the eyepiece is 10x, than the magnifying power of the eyepiece is 100x 10 = 1000 ie the companion of t If the power of the objective lens is 10x, than the magnifying power and that the eyepiece is 10x, than the magnifying rand that microscope is 100x 10 = 1000 is the object 1000 times. Compound microscope is 1000 in the row microscope magnifies the object 1000 times.

The ability of the microscope to distinguish two The ability of the interescope to distinguish two is called 'Resolving power of the microscope to distinguish the microscope entities is called 'Resolving power of the microscope is imposed in the microscope is imposed.

The resolving power of the microscope is improved by the following factors.

- 1. High numerical aperture.
- 2. Fully opened condenser (diaphragm). 3. Shorter wavelength of light (blue light). 4. Immersion fluid like oil.

Numerical aperture (NA)

Numerical aperture is light gathering capacity of the lens. The NA of the lens is inscribed in the metal tube

The higher the NA, the better the light gathering properties and the better resolving power.

Higher NA values also mean shorter working distances (you can bring the lens closer to the object).

NA values above 1.0 also indicate that the lens is used with some immersion fluid such as oil immersion.

The compound microscope has the following parts:

1. Reflecting mirror: It reflects light on the object. 2. Condenser: It focuses the reflected light on the object. The condenser has a diaphragm. It allows the required intensity of light to pass through.

3. Objective lens: It magnifies the object.

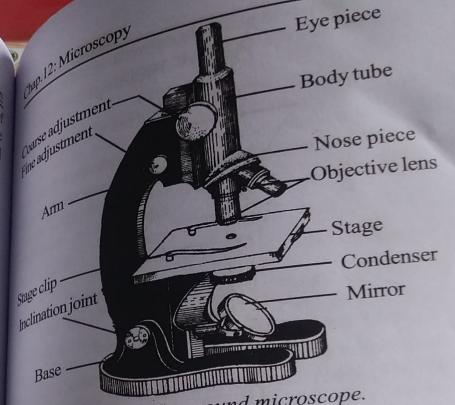


Fig.12.3: Compound microscope.

4. Eye piece: It magnifies the image produced by

5. Body tube: It is a tube with the objective lens at the objective lens. the lower end and the eye piece at the upper end.

6. Coarse adjustment: It moves the body tube up and down rapidly to correct the distance from the object

7. Fine adjustment: It moves the body tube up and to get focussing. down slowly to make exact focussing.

8. Stage: It is a platform with a hole in the centre. The light falls on the object through the hole. The slide is placed on the stage.



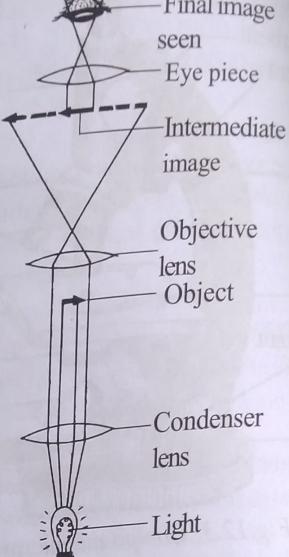


Fig.12.4: Components of a compound microscope.

9. Stage-clips: Stage-clips hold the slide firmly on the stage.

10. Nose-piece: It is in the form of a rotating disc

having holes for fitting the objective lenses.

11. Arm: It holds body tube and coarse adjustment.

12. Inclination joint: It permits tilting of the upper part of the microscope to adjust to the level of eye.

13. Base or Foot: The first keeps the body in

position.

3. It is used to examine water and other fluids for the presence of minute transparent microbes (bacteria and flagellates).

4. It is a must to study physiological processes such as *phagocytosis*, *pinocytosis*, *cell divisions*, etc. in cells

5. It is used to study the behaviour of chromosomes during *mitosis* and *meiosis*.

6. It is best to study living cells without fixation and staining.

2. Electron Microscope

Electron microscope is a system of electromagnetic coils where electron beam is used as the source of illumination.

As the wave length of electron is very short (0.05A°), the magnification is very high. Electron microscope gives a magnification of 2000 times than that of light microscope.

It is much useful in studying virus, bacteria and the ultrastructure of cell organelles.

The first electron microscope was designed by Knoll and Ruska in 1932.

There are two types of electron microscopes, namely transmission electron microscope (TEM) and scanning electron microscope (SEM).

In transmission electron microscope, the electron beam is transmitted through the ultra thin object.

In scanning electron microscope, the electron beam scans the surface of the object and conveys its image to a TV screen. When the electron beam strikes the object it penetrates a few micrometres into its surface and liberates low energy 2° electrons. A secondary electron detector low energy 2° electrons. A secondary electron detector traps the signals and converts them into a 3-D image of

chap. 12: Microscopy

the TV screen. SEM can also provide information about chemical composition of the specimens.

principle

Principle

Electron microscope uses electron be

Electron microscope uses electron beam as the illuminating source.

The electron beam has very

The electron beam has very short wavelength fanging from 0.05 Å to 0.005 Å. So the resolving power sayery high. It can magnify objects up to 2 million times.

Servery high is a straight line in vacuum because

the electrons move in a straight line in vacuum because

The electrons are produced by an electron gun

containing a tungsten filament. The filament is heated to

release electrons.

The lenses used in electron microscope are collected.

The lenses used in electron microscope are called electromagnetic coils. They work on electric current.

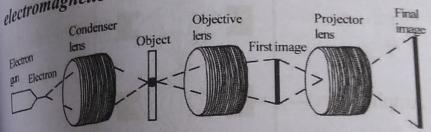


Fig.12.10:Principle of electron microscope.

• Two condenser lenses are kept on the path of the electrons. They make the electrons into a narrow beam and focus on the object.

• The brighter and finer the electron beam, the higher the level of observation of the object.

• The object absorbs, diffracts, reflects and transmits the electrons.

• The *image* results from the scattering of electrons by the atoms present in the specimen.

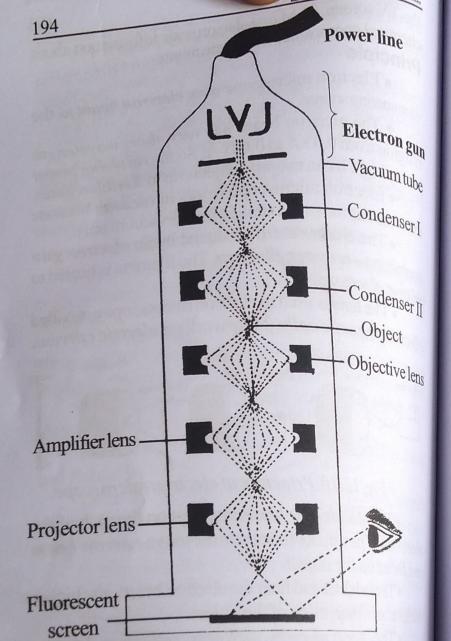


Fig. 12.11: Transmission electron microscope.

• A heavy atom is more effective in scattering of electrons than one of low atomic number.

The presence of heavy atoms will increase the image contrast. Hence the electron microscopists incorporate heavy atoms like gold into the specimen.

The part of the specimen which The part of the specimen which transmits elec-

pons appears bright. The portions of specimen which absorb or scatter electrons appear dark.

The objective lens collected

The objective lens collects the image of the speci-

men and focuses it towards the amplifier lens. The amplifier lens magnifies the image several

1000 times. • A projector lens focuses the image on a photo-

graphic plate.
Structure

The electron microscope consists of the following

components:

1. Electron gun

2. Condenser Lenses

3. Object

4. Objective coils

5. Amplifier coils

6. Projector coils

7. Fluorescent screen or photographic plate

8. Vacuum tube

9. Cooling system

1. Electron Gun: Electron gun is the source of illumination. It consists of a V- shaped filament and two circular metal plates with holes in the centre. The two metalplates are named as cathode shield and anode plate. Ahigh voltage is applied between the filament and the anode plate. A current flows through the filament and heats it to incandescence, causing it to emit electrons. The electrons are attracted towards the anode plate and

they pass through the hole in its centre. The cathode shield the electrons in the form of a beam through they pass through the form of a beam through the shield anode plate.

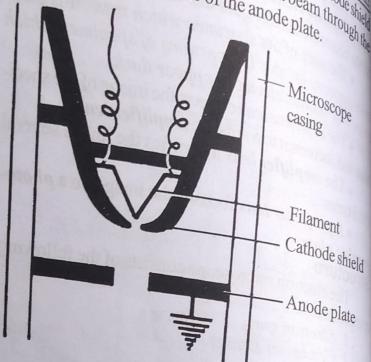


Fig.12.12: Electron gun.

- 2.Condenser Lenses: There are two condenser lenses set one below the other. Each lens is a coil of wire called electromagnetic coil or electromagnetic lens. They make the electron beam very narrower and focus the beam in the direction of object.
- 3. Object: The object is placed below the second condenser lens in the focal length of the beam. The object is placed on a supporting film mounted on a copper
- 4. Objective Lens: It is another electromagnetic coil, situated below the object. It captures the transmitted

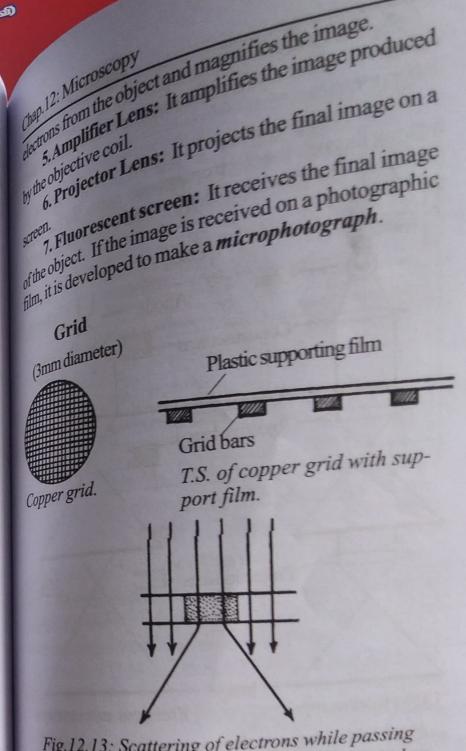


Fig.12.13: Scattering of electrons while passing through dense region of the specimen but not in less dense region.

8. Vacuum tube: The entire set-up is placed in a straight in a

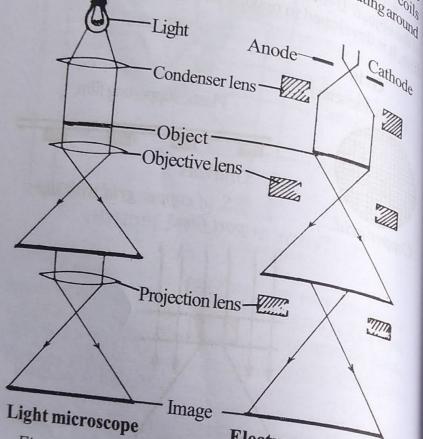
8. Vacuum tube: The entire set-up is placed in a vacuum.

Vacuum tube, because the electrons move in a placed in a straight line

Moderately laroa ma vacuum.

9. Cooling system: Moderately large current is through the electromagnetic coils. So the coil. 9. Cooling system.

1. The Coo flowing through the electromagnetic coils. So the entities the table of the coils are cooled by water circulating around



Electron microscope Fig.12.14: Diagram showing the optical parts of light and electron microscopes.

arison of Electron and Light

12: Microscopes. Microscopes.	Light Microscope
ap'/ Coroscop	Tungston lamp or
Electron Microm a Electron beam from a Electron beam from a	Glass or quartz lens
Electron Electron high voltage system high voltage system	More than 50000A° and 500000A° thick.
- mai	Image on ground glass
thick on fluorescent	Works in air column
object screen court	Viewed immediately
Requires one note	Live materials also
Spring High 1.5A°. 2000 times high 1.5A°. 2000 times	Low 2000A [®]
Reallying light microscope short wavelength	Long wavelength radiations
radiations radiations	5000A° upright.
wavelength radiations 0.5 to .05A° inverted	=1 -duam

1. Transmission Electron **Microscope** (TEM)

Electron microscope in which electron beam is passed through the specimen to produce its image is called ransmission electron microscope (TEM).

The first TEM was designed by Max Knoll and Ernst Ruska in 1931.

The TEM was first made available in the market in 1939.

The TEM has wide applications in the research on virology, oncology, pollution studies, material science and semi-conductor research.

Principle

The basic principle of electron microscopes is sink lar to the optical principle of ordinary compound nico scope. Here, electron beam is substituted for light beam and electromagnetic coils are substituted for optical

க்கழக் வ

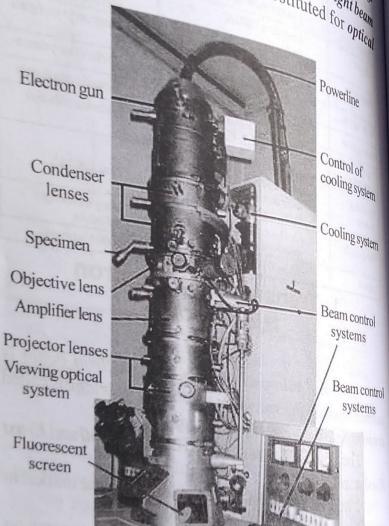


Fig. 12.15: Photograph of a transmission electron microscope.

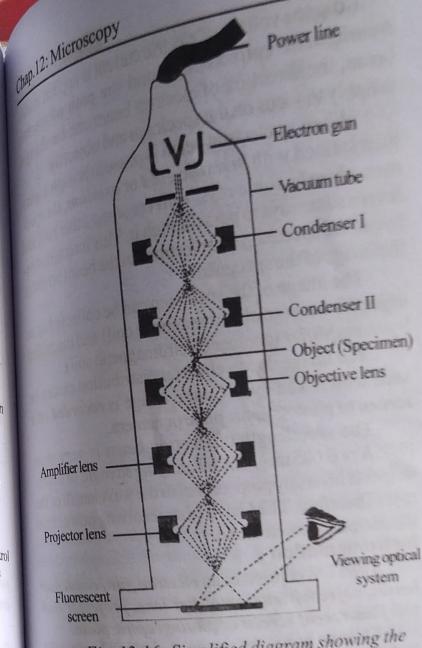


Fig. 12.16: Simplified diagram showing the electron path of TEM.

When high voltage current is passed through a filament of cathode ray tube, electron beams are produced from the filament.

If some voltage of electric current is applied to electromagnetic coils kept around the path of electron beam, the direction of electron beam can be changed suitably to focus on the specimen and objective.

When an electron beam is passed through a speci.

men stained with metallic gold or osmium, the specimen stained with men absorbs some rays, reflects some other rays and men absorbs some rays, reflects some other rays and men absorbs some rays to pass through it. This interaction be. tween the specimen and electrons in the beam produces the image of the specimen.

The image of the specimen can be collected by an objective lens (an electromagnetic coil) and magnified by an amplifier (another electromagnetic coil).

The image due to electron distribution cannot be seen with naked eyes. So the image is recorded on a screen or photographic plate or camera.

The wavelength of electron beam is very short (0.05A or 0.005 nm). The magnifying strength of micro. scopes is inversely proportional to the wavelength of the rays. Therefore, TEM has higher resolving power than the compound microscope.

Instrumentation

ode.

The TEM consists of an electron gun, condenser lenses, objective lens, amplifier lens, projector lens and fluorescent screen or photographic plate.

Electron gun is the source of electron beam used in this microscope. It consists of a V-shaped filament, Whenelt cylinder and an anode plate with a hole at the centre. The Whenelt cylinder is a small cup-like structure with a hole at the bottom. The V-shaped filament is kept in the cup. The Whenelt cylinder acts as a cath.

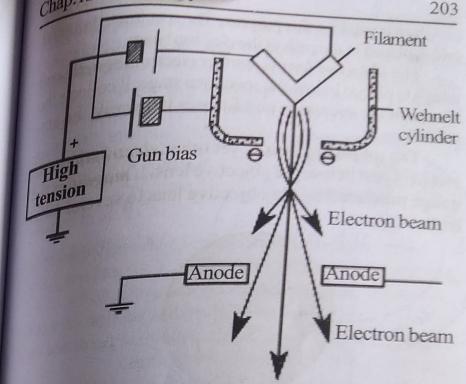


Fig. 12.17: Electron gun.

When high voltage current is applied between the filament and anode plate, the filament is heated up to incandescence for emitting electrons. Since the electrons are attracted towards the anode, they are forced out through the hole in the anode plate by the cathode shield. The electron gun is placed at the top of the TEM.

There are two condenser lenses just below the electron gun. They are nothing but electromagnetic coils (coil of wires). They collect and concentrate the electrons into astrong electron beam before focusing it onto the specimen.

Just below the second condenser lens, there is a specimen stage. A thin section of specimen is placed on a thin plastic film mounted on a copper grid. The grid size of 2.2nm

Preparation are formed of elements of rela
The preparation are formed of elements are carbon

The elements are carbon

The preparation are formed of elements are carbon

The elements are carbon Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements of relations are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens and nitrogen.

They are a specimens and nitrogen.

Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens and nitrogen.

Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are formed of elements are carbon, hy
Jan ple is a specimens are Bolly atomic weight. The elements are carbon, hyThey do not give high
They do not give They do not give high

They do not give high

Therefore,

Ther Therefore, and the state of the politic gical sample has to be roaded with heavy atoms

The heavy atoms the how gold or osmum via fixation. The heavy atoms the destructive effects of the specimen from the destructive effects of the specimen from the destructive effects of the specimen in the TEM. ***** 34613 proteon in the TEM.

Fig.12.18: Copper grid (3mm diametre).

GO BULD - C

A projector lens collects the magnified image and focuses it onto a fluorescent screen or photographic

The entire setup is placed in a vacuum tube, be. cause electrons can move in a straight line only in a vacuum. Usually, vacuum pressure of 10^{-7} to 10^{-9} $P_{a is}$

While TEM is working, a large amount of heat is flowing through the electromagnetic coils. As a consequence, the TEM is heated to a great extent. In order to keep the apparatus at a low temperature, cooling water is circulated through a cooling system around the TEM.

Fig.12.19: Electron micrograph of section of Bacillus subtilis taken by TEM.

The sample preparation and examination involve the

• The wet specimen is dehydrated (water removal) following steps: by keeping in increasing concentrations of ethanol or

• Fixation is a chemical processing of biological specimens. It stabilizes the molecular organizations as such acetone. in them. It is done by immersing the specimen in chemical preservatives called fixatives for a considerable time. Osmium tetroxide, glutaraldehyde, potassium per-

manganate, formalin, etc. are common fixatives form covalenthal manganate, formaun, etc. are common fixatives form covalent biological molecules like proteins and lipids. The with biological molecules like proteins and lipids. The specimen

with biological more and process and lipids After fixation, the specimen is embedded in a like araldite or vestopal-Work. After madium, in speciment of more ded in a half of the stop al-W or Epson.

The embedded specimen is cut into thin sections thickness using a glass or dimension. of 50-100nm thickness using a glass or diamond

• The thin section is mounted on a copper grid of 3mm diameter and covered with

• This section is then kept dipped in a solution containing heavy metal ions for metallic staining. Solutions of phosphotunstate, lead acetate, lead hydroxide, os. mium tetroxide, etc. are useful for this staining. These me. tallic stains give clear contrast to the specimen.

• The specimen-mounted grid is then placed on the specimen stage between the condenser coil and object

• Image of the specimens is viewed through the optical system to choose a suitable section.

• Image of the selected section is then viewed on the fluorescence screen or captured in photographic plate.

1. TEM is an ideal tool for the study of ultrastructure of cells.

2. It is used in the *identification* of plant and animal viruses based on their structural features.

3. It is employed in the *localization* of nucleic acid, enzymes and proteins in cells and cell organelles.

12: Micro ancer research for the cytological

4. It is used in cancer cells. Chap. 12: Microscopy Senation of Canoning Electron Microscope (SEM) been of cancer cells. Electron microscope that scans the surface of speci-Electron mer surjace of speci-Blev by passing an electron beam is called scanning elec-Blev by passing an electron beam is called scanning elecmel by passing an exemple seem. The first SEM was designed by microscope (SEM). The first SEM was designed by Knoll in 1935. It scans the surface of specimen using electron beam Max Knoll in 1935.

It scans the same scanning the surface of paper by

The SEM is very useful to laser beam. The SEM is very useful to study the surface architecture of cells, membranes, organelles and others.



Fig.12.20: Photograph of scanning electron microscope.

Principle

The SEM also uses an electron beam as illumination and electromagnetic coils to direct the path of electron beam.

When electron beam is focused on the specimen, it produced electrons (SE), back-scattered electrons When electron beams to the specimen specimen and characteristic X-rays.

The secondary electrons are those which are reflected The secondary electrons between the atoms at the surface of the

The electrons reflected by the sample due to its elastic The electrons reflected back-scattered electrons scattering property are called back-scattered electrons scattering property are called back-scattered electrons (BSE). The BSE gives information about the distribution

Characteristic X-rays are emitted by the sample when the electron beam removes electrons in the inner shells of the

The SE, BSE and characteristic X-ray are detected accurately using separate specialized detectors. The beam current absorbed by the specimen is detected and used to create the current distribution in the specimen.

Electronic amplifiers of different kinds (collecter, scintillator and PMT) are used to measure the electric signals. The electric signals are converted into bright spots of varying density by a scanning circuit to give the image of the specimen on the screen.

Instrumentation

The SEM consists of an electron gun, two condenser coils, objective lens (coil), specimen stage, grid, scintillator, photomultiplier tube (PMT), scanning circuit and x-ray detector.

Electron gun is the source of electron beam used in this microscope. It consists of a V-shaped filament, Whenelt cylinder and an and plate with a hole in the centre. The Whenelt cy mall cup-like struc-

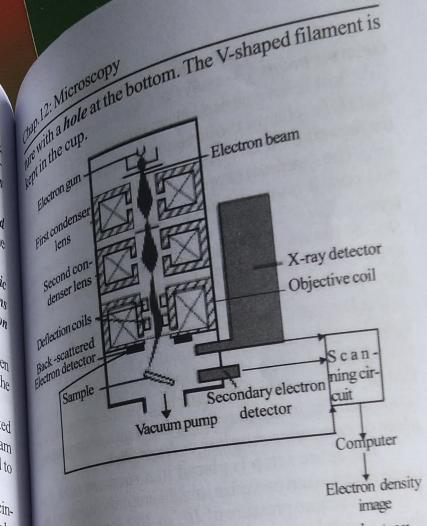


Fig.12.21: Schematic structure of scanning electron microscope.

The Whenelt cylinder acts as a cathode. When high voltage current is applied between the filament and anode plate, the filament is heated up to incandescence for emitting electrons. Since the electrons are attracted towards the anode, they are forced out through the hole in the anode plate by the cathode shield. The electron gun is placed at the top of the SEM.

There are two condenser lenses just below the electron gun. They are electromagnetic coils (coil of wires).

They collect and concentrate the electrons into a strong

Just below the second condenser, there is a deflection of electron path, It hall Just below the second condense, there is a deflection of electron path. It helps for focusing the electron beam on the specimen stage is placed just below the dean The specimen stage is placed just below the deflection position (45°) in the election The specimen stage to place of Just octow the deflection coil. It is in a slanting position (45°) in the electron

Separate electron detectors are attached to the vacuum tube of SEM. Each of these electron detector is formed of a collector, a scintillator and PMT.

Electronic amplifiers are connected with the detection of tors. They are used to measure the electric signals. The electric signals are converted into bright spots of varying density by a scanning circuit to give the image of the specimen. The image may be captured on a photographic plate or computer monitor or hard disk.

The entire setup is placed in a vacuum tube, because electrons can move in a straight line only in a vacuum. Usually, vacuum pressure of 10-7 to 10-9 Pa is applied to

While SEM is working, a large amount of heat is flowing through the electromagnetic coils. As a consequence, the SEM is heated to a great extent. In order to keep the apparatus at a low temperature, cooling water is circulated through cooling system around the SEM.

Dry materials such as wood, bone, feathers, insect's wings and shells are coated with a thin film of electroconductive material. Generally, metallic gold, platinum, tungsten, iridium, osmium, chromium and

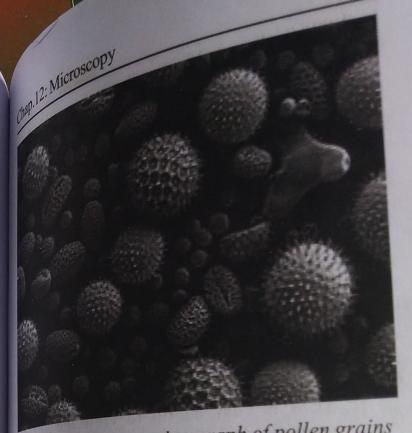


Fig.12.22: Electron micrograph of pollen grains taken by using SEM.

Then, the specimen is placed on a grid to place it on the specimen stub.

The preparation of wet specimen for SEM examination involves the following steps:

• Wet specimen is fixed by immersing it in a solution of fixatives. The fixation stabilizes the molecular organizations as such in them. Osmium tetroxide, glutaraldehyde, potassium permanganate, formalin, etc. are common fixatives for biological specimens. These fixatives form covalent bonds with biological molecules such as proteins and lipids to stabilize their structural organization.

- After chemical fixation, the specimen is dehydrated (water removal) by keeping it is increasing concentrations of *ethanol* or *acetone*.
- The specimen is then coated with an ultra thin layer of electroconductive alloy. This metallic coating prevents the accumulation of electrostatic charges on the specimen.

• The specimen is placed in slanting position on the specimen holder called specimen stub.

- When electron beam is focused on the specimen, the SEM detects the secondary electrons, back-scattered electrons, X-ray emission.
 - The image is formed on the computer monitor,

Applications of SEM

- 1. SEM is very useful to view the surface architecture of microscopic creatures like bacteria, diatoms, pollen grains, nematodes and others.
- 2. SEM gives the 3-D structure of objects to reveal the structure of organism or organelles.
- 3. SEM is employed in the analysis of structural features of compound eyes of insects.
- 4. Hairs and scales on plant and animal surfaces are characterized with the SEM.
- 5. SEM is used to study the surface of small archeological specimens and fossils.